

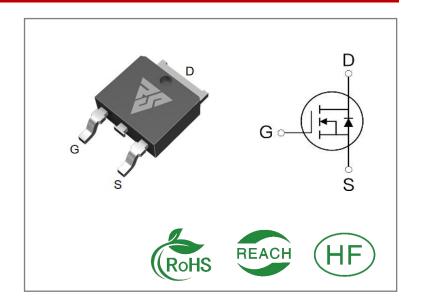
ID	R _{DS} (ON)(Typ)	VDSS
5A	1.8Ω	650V

Applications:

- Switch Mode Power Supply(SMPS)
- Adapter & Charger
- AC-DC Switching Power Supply

Features:

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability



Ordering Information

Part Number	Package	Marking	Packing	Qty.	
RS5N65D	T0-252	RS5N65D	Tape&reel	2500 PCS	

Absolute Maximun Ratings Tc= 25°C unless otherwise specified

Symbol	Parameter	RS5N65D	Units
VDSS	Drain-to-Source Voltage	650	V
ID	Continuous Drain Current TC=25℃	5	^
IDM	Pulsed Drain Current (Note*1)	20	A
PD	Power Dissipation	90	W
VGS	Gate- to- Source Voltage	±30	V
EAS	Single Pulse Avalanche Engergy L = 10mH, VDD = 50V, RG = 25 Ω	105	mJ
TI TRICO	Maximum Temperature for Soldering	300	
TL TPKG	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds	260	$^{\circ}$
TJ and TSTG	Operating Junction and Storage Temperature Range	-55 to 150	

 $^{^{\}ast}$ Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" Table may cause permanent damage to the device.



Thermal Resistance

Symbol	Parameter	RS5N65D	Units	Test Conditions
				Drain lead soldered to water cooled
RθJC	Junction-to-Case	1.27		heatsink, PD adjusted for a peak
			°C/W	junction temperature of + 1 5 0 $^{\circ}{\rm C}$
RθJA	Junction-to-	62.5		1 cubic foot chamber,free air.
KOJA	Ambient	62.3		1 cubic foot chamber,free air.

OFF Characteristics TJ= 25° C unless otherwise specified

Symbol	Parameter		Тур.	Max.	Units	Test Conditions
BVDSS	Drain- to- source Breakdown Voltage				V	VGS=0V,ID=250μA
IDSS	Drain- to- Source Leakage Current			1	μΑ	VDS=650V,VGS=0 V
	Gate- to- Source Forward Leakage	kage 100			VGS=30V ,VDS=0V	
IGSS	Gate- to- Source Reverse Leakage			-100	nA	VGS=-30V ,VDS=0 V

ON Characteristics TJ=25 °C unless otherwise specified

Symbol	Parameter		Тур.	Мах.	Units	Test Conditions
RDS(on)	Static Drain- to- Source On- Resistance(Note*2)		1.8	2.1	Ω	VGS=10V,ID=2.5A
VGS(TH)	Gate Threshold Voltage	3		4	V	VGS=VDS,ID=250μ A

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter		Тур.	Max.	Units	Test Conditions
td(ON)	Turn- on Delay Time		35			
trise	Rise Time		8			VDS=325V
td(OFF)	Turn- OFF Delay Time		60		nS	ID=5A RG=25Ω
tfall	Fall Time		25			



Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
Ciss	Input Capacitance		665	1		VGS=0V
Coss	Output Capacitance		64		pF	VDS=25V
Crss	Reverse Transfer Capacitance		6.5			f=1.0MHz
Qg	Total Gate Charge		20			VDS=520V
Qgs	Gate- to- Source Charge		3		nC	ID=5A
Qgd	Gate-to-Drain(" Miller") Charge		11.5			VGS=10V

Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
IS	Continuous Source Current	Continuous Source Current		5	Α	Integral pn- diode
ISM	Maximum Pulsed Current			20	Α	in MOSFET
VSD	Diode Forward Voltage			1.4	٧	IS=2.5A,VGS=0V
trr	Reverse Recovery Time		320		nS	VGS=0V
Qrr	Reverse Recovery Charge		2.74		μС	IS=5A,di/dt=100A/ μs

Notes:

^{* 1.} Repetitive rating, pulse width limited by maximum junction temperature.

^{* 2.} Pulse Test: Pulse width ≤ 300µs, Duty Cycle ≤ 1%



Typical Feature Curve

Figure 1. Output Characteristics (T_J = 25°C)

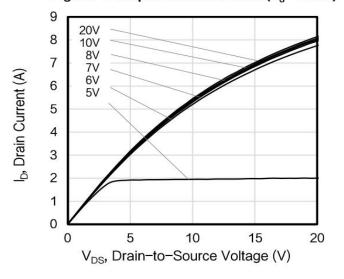


Figure 2. Body Diode Forward Voltage

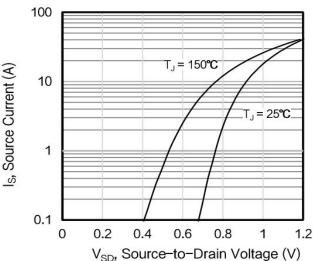


Figure 3. Drain Current vs. Temperature

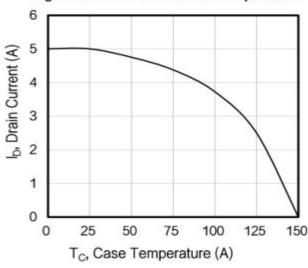


Figure 4. BV_{DSS} Variation vs. Temperature

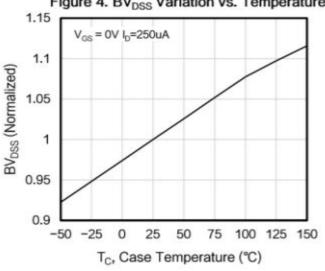


Figure 5. Transfer Characteristics

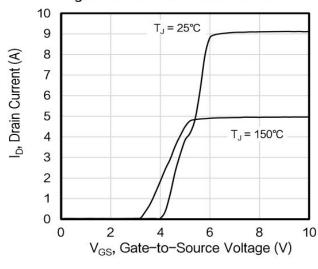
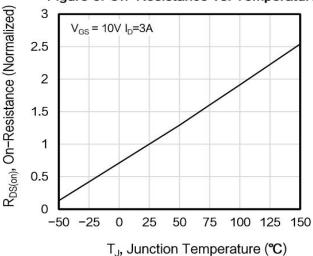
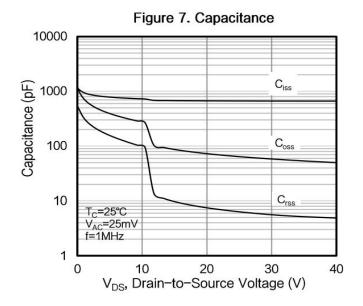


Figure 6. On-Resistance vs. Temperature



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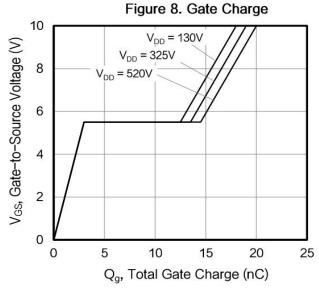


Figure 9. Transient Thermal Impedance

1E+1

(W)

1E+0

90

1E+1

D = 0.5

D = 0.2

D = 0.1

D = 0.05

D = 0.02

D = 0.01

Single
Pulse

T_p, Pulse Width (s)



Test Circuits and Waveforms

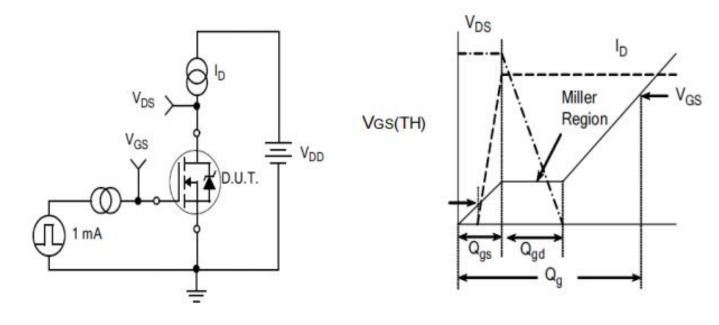


Figure 10.
Gate Charge Test Circuit

Figure11.
Gate Charge Waveform

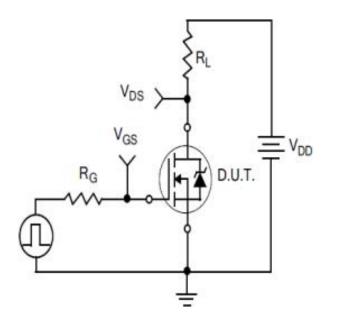


Figure12.
Resistive Switching Test Circuit

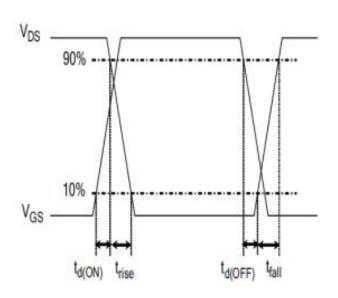


Figure 13.
Resistive Switching Waveforms



Test Circuits and Waveforms

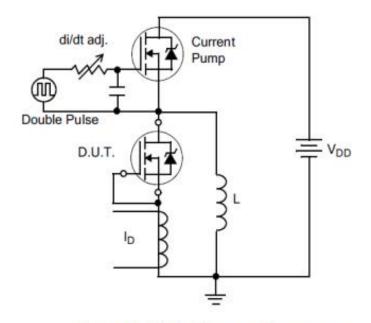


Figure 14. Diode Reverse Recovery
Test Circuit

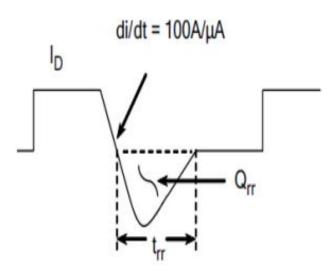


Figure 15. Diode Reverse Recovery Waveform

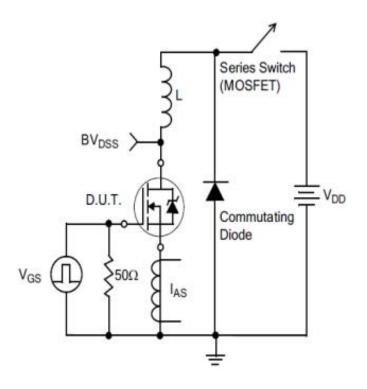
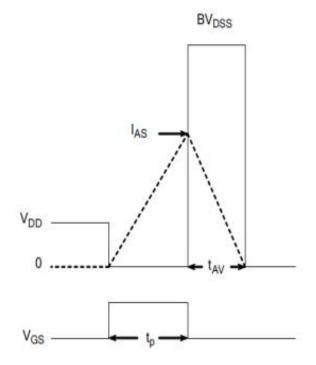
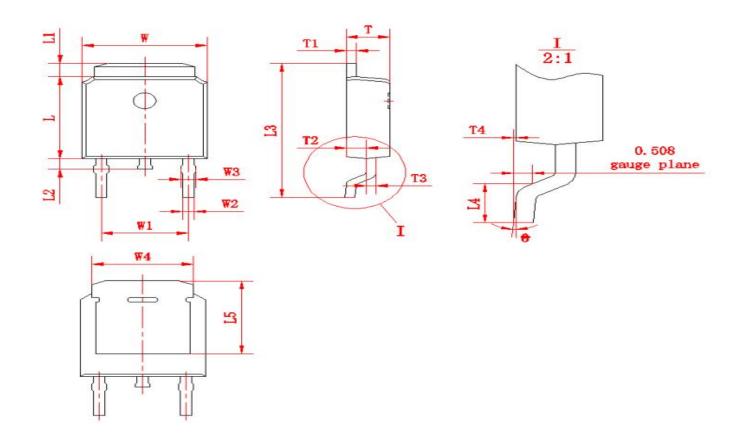


Figure 16. Unclamped Inductive Switching Test Circuit





Package outline drawing(TO-252 Unit: mm)



符号	尺	寸			尺寸		尺寸	
<u>च</u> क	Min	Max	符号	Min	Max	から	Min	Max
W	6.50	6.70	L1	0.80	1.20	T1	0.48	0.58
W1	(4.5	572)	L2	0.60	0.60 1.00		0.95	1.15
W2	0.6	0.8	L3	9.70	10.30	Т3	0.48	0.58
W3	0.68	0.88	L4	1.30	1.70	T4	0.00	0.12
W4	(5	.3)	L5	(5.20)		0	0	8
L	6.00	6.20	Т	2.20	2.40			



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